A Low-Voltage MOS Cascode Bias Circuit for All Current Levels

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- Cascodes are alive and well, but we must bias them properly for low-voltage operation.
- How can we generate V_{cn} and V_{cp} without consuming too much headroom?







• We model the channel current of an *n*MOS transistor as the difference between a *forward* current and a *reverse* current,

$$I=I_{\rm F}-I_{\rm R},$$

whose values are given by

$$I_{\rm F(R)} = \frac{W}{L} I_{\rm s} \log^2 \left(1 + e^{\left(\kappa (V_{\rm G} - V_{\rm T0}) - V_{\rm S(D)}\right)/2U_{\rm T}} \right),$$

where

$$U_{\rm T} \equiv \frac{kT}{q}, \quad I_{\rm s} \equiv \frac{2\mu C_{\rm ox} U_{\rm T}^2}{\kappa}, \quad \text{and} \quad \kappa \equiv \frac{C_{\rm ox}}{C_{\rm ox} + C_{\rm dep}}.$$

• Note that $\kappa \equiv 1/n$ and that I_s is approximately twice the threshold current of a square transistor.





- The model covers all regions of MOS transistor operation and is continuous and smooth.
- The expression reduces asymptotically to an exponential in weak inversion and a quadratic in strong inversion, given by



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- We define the onset of saturation operationally in terms of an arbitrary parameter, $A \gg 1$: We say that an MOS transistor is saturated if and only if $I_F/I_R \ge A$.
- To find an explicit expression for V_{DSsat} , we write that

$$A = \frac{I_{\rm F}}{I_{\rm R}} = \frac{\log^2 \left(1 + e^{(\kappa (V_{\rm G} - V_{\rm T0}) - V_{\rm S})/2U_{\rm T}}\right)}{\log^2 \left(1 + e^{(\kappa (V_{\rm G} - V_{\rm T0}) - V_{\rm S} - V_{\rm DSsat})/2U_{\rm T}}\right)}.$$





• Solving for V_{DSsat} , we find that

$$\begin{split} V_{\text{DSsat}} &= \kappa \left(V_{\text{G}} - V_{\text{T0}} \right) - V_{\text{S}} - 2U_{\text{T}} \log \left(\left(1 + e^{(\kappa (V_{\text{G}} - V_{\text{T0}}) - V_{\text{S}})/2U_{\text{T}}} \right)^{1/\sqrt{A}} - 1 \right) \\ &= 2U_{\text{T}} \log \left(\frac{e^{\sqrt{I_{\text{F}}/(W/L)I_{\text{S}}}} - 1}{e^{\sqrt{I_{\text{F}}/A(W/L)I_{\text{S}}}} - 1} \right) \\ &\approx \begin{cases} U_{\text{T}} \log A, & V_{\text{G}} < V_{\text{T0}} + \frac{V_{\text{S}}}{\kappa} \\ \left(1 - \frac{1}{\sqrt{A}} \right) \left(\kappa \left(V_{\text{G}} - V_{\text{T0}} \right) - V_{\text{S}} \right), & V_{\text{G}} > V_{\text{T0}} + \frac{V_{\text{S}}}{\kappa}. \end{cases} \end{split}$$











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• Solving for $I_{\rm F2}/I_{\rm R2}$, we get

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$$\frac{I_{\rm F2}}{I_{\rm R2}} = 1 + \frac{I_2}{I_{\rm R2}} = 1 + m\frac{I_2}{I_1} = 1 + m\left(1 + \frac{I_{\rm b}}{I_1}\right).$$





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- If we choose *m* to be even, we can optimally share source/drain regions of the *n*MOS transistors in the bias circuit.
- If we choose n = m + 1, we have as many *p*MOS strips as *n*MOS strips.

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